

ESD RELIABILITY TEST REPORT

TEST REPORT

Company : LINSN TECHNOLOGY
Address : 5/F, Xinhaofang Bldg., No.188 Shennan Rd., Nanshan District, Shenzhen City, Guangdong Province, P.R. China.
Sample Name : LXY28161
Date of Received : May 28, 2008
Date of Tested : May 28, 2008

TESTING LABORATORY IS ACCREDITED BY:

IEC/IECQ 17025 certificate of independent test laboratory approval
Certificate No. : T1117

WE HEREBY CERTIFY THAT:

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

	Name	Signature	Date
Testing Engineer	Jianbo Song	<i>Jianbo Song</i>	2008/5/28
Approving Manager	Alston Wang	<i>Alston Wang</i>	2008/5/28
Vice President	Coming Chen	<i>Coming Chen</i>	2008/5/28

Note :

1. This report will be invalid if reproduced in whole or in part.
2. This report refers only to the specimen(s) submitted to test, and is invalid if used separately.
3. This report is ONLY valid with the examination seal and signature of this institute.
4. The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant.



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No.:T1117

Report No. : SH0805280002HE-CN

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Applicant/Department: LINSN TECHNOLOGY.	
Product : LXY28161	Sample Size : <u>12</u> (units)
Testing Item : ESD-HBM	Package/Pin Count: SSOP/24
Test Method : MIL-STD-883G Method 3015.7	
Failure Criteria : FOR V CHANGE AT 1 μ A \pm 30%	
Test Voltage : 4000V~8000V, Step: 500V(\pm).	



ESD-HBM Testing Report

Test Equipment:

KEYTEK ZAPMASTER 7/4

Test Equipment S/N:

9608430

Calibration Date:

June 22, 2007

Recommended Due Date:

June 21, 2008

Environmental Condition of Laboratory:

Temperature: 25°C±5°C

Humidity: 55%±10% RH

Test Condition:

IO VCC TO VSS (+)
IO VCC TO VSS (-)
IO VSS TO VCC (+)
IO TO IO (+)

Test Result:

MODEL: HBM	ESD SENSITIVITY PASS : ±6500V		V CLASS: 3
PIN COMBINATION	SAMPLE SIZE	PASSED VOLTS	NOTE:
IO VCC TO VSS (+)	3	+7500	FOR EIAJ TEST NO CLASSIFICATION CLASS 0: < 250V CLASS 1A: 250V TO 499V CLASS 1B: 500V TO 999V CLASS 1C: 1000V TO 1999V CLASS 2: 2000V TO 3999V CLASS 3A: 4000V TO 7999V CLASS 3B: ≥ 8000V
IO VCC TO VSS (-)	3	-6500	
IO VSS TO VCC (+)	3	+8000	
IO TO IO(+)	3	+8000	

VCC: Pin24;
VSS: Pin1;
IO: Pin2-23;

		IO VCC TO VSS (+)			(UNIT:V)
Test Pin	FAIL VOLTAGE	#1-1	#1-2	#1-3	
	2	PASS	PASS	PASS	
	3	PASS	PASS	PASS	
	4	PASS	PASS	PASS	
	5	PASS	PASS	PASS	
	6	8000	PASS	PASS	
	7	PASS	PASS	PASS	
	8	8000	8000	PASS	
	9	PASS	PASS	PASS	
	10	PASS	8000	PASS	
	11	PASS	8000	PASS	
	12	PASS	PASS	PASS	
	13	PASS	PASS	PASS	
	14	PASS	PASS	8000	
	15	PASS	8000	PASS	
	16	PASS	PASS	8000	
	17	PASS	PASS	PASS	
	18	PASS	PASS	PASS	
	19	8000	PASS	PASS	
	20	PASS	PASS	PASS	
	21	PASS	PASS	PASS	
	22	PASS	PASS	PASS	
	23	PASS	PASS	PASS	
	24	PASS	PASS	PASS	

		IO VCC TO VSS (-)			(UNIT:V)
Test Pin	FAIL VOLTAGE	#2-1	#2-2	#2-3	
	2	PASS	PASS	PASS	
	3	PASS	PASS	PASS	
	4	PASS	PASS	PASS	
	5	PASS	PASS	PASS	
	6	PASS	PASS	PASS	
	7	PASS	PASS	PASS	
	8	PASS	PASS	PASS	
	9	PASS	PASS	PASS	
	10	PASS	PASS	PASS	
	11	PASS	PASS	PASS	
	12	PASS	PASS	PASS	
	13	PASS	PASS	PASS	
	14	PASS	PASS	PASS	
	15	PASS	PASS	PASS	
	16	PASS	PASS	PASS	
	17	PASS	PASS	PASS	
	18	PASS	PASS	PASS	
	19	PASS	PASS	PASS	
	20	PASS	PASS	PASS	
	21	PASS	PASS	PASS	
	22	7000	7000	7500	
	23	PASS	PASS	PASS	
	24	7000	PASS	7500	

		IO VSS TO VCC (+)			(UNIT:V)
Test Pin	FAIL VOLTAGE	#3-1	#3-2	#3-3	
	1	PASS	PASS	PASS	
	2	PASS	PASS	PASS	
	3	PASS	PASS	PASS	
	4	PASS	PASS	PASS	
	5	PASS	PASS	PASS	
	6	PASS	PASS	PASS	
	7	PASS	PASS	PASS	
	8	PASS	PASS	PASS	
	9	PASS	PASS	PASS	
	10	PASS	PASS	PASS	
	11	PASS	PASS	PASS	
	12	PASS	PASS	PASS	
	13	PASS	PASS	PASS	
	14	PASS	PASS	PASS	
	15	PASS	PASS	PASS	
	16	PASS	PASS	PASS	
	17	PASS	PASS	PASS	
	18	PASS	PASS	PASS	
	19	PASS	PASS	PASS	
	20	PASS	PASS	PASS	
	21	PASS	PASS	PASS	
	22	PASS	PASS	PASS	
	23	PASS	PASS	PASS	

		IO TO IO (+)			(UNIT:V)
Test Pin	FAIL VOLTAGE	#4-1	#4-2	#4-3	
	2	PASS	PASS	PASS	
	3	PASS	PASS	PASS	
	4	PASS	PASS	PASS	
	5	PASS	PASS	PASS	
	6	PASS	PASS	PASS	
	7	PASS	PASS	PASS	
	8	PASS	PASS	PASS	
	9	PASS	PASS	PASS	
	10	PASS	PASS	PASS	
	11	PASS	PASS	PASS	
	12	PASS	PASS	PASS	
	13	PASS	PASS	PASS	
	14	PASS	PASS	PASS	
	15	PASS	PASS	PASS	
	16	PASS	PASS	PASS	
	17	PASS	PASS	PASS	
	18	PASS	PASS	PASS	
	19	PASS	PASS	PASS	
	20	PASS	PASS	PASS	
	21	PASS	PASS	PASS	
	22	PASS	PASS	PASS	
	23	PASS	PASS	PASS	